

Q8/10/04 TUE 12:24 FAX 281 834 1231

ECLT FORMALITIES BPC

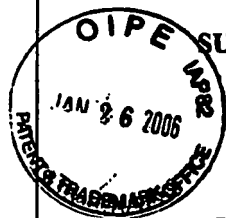
0018

FORM - 1449

SHEET 16 OF 35

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				COPY DOCKET NO.		SERIAL NO.	
				2003B043C		10/825,349	
				APPLICANT			
				Abhari et al.			
				FILING DATE		GROUP	
				April 15, 2004		1713	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	PUBL. DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
KW	MK	2001/0047064	11/29/01	Sun			
	ML	2001/0053837	12/20/01	Agarwal et al.			
	MM	2002/046054 0045054	04/18/02	Uhara et al.			
	MN	2002/049136 0049135	04/25/02	Moody et al.			
	MO	2002/061946 0061945	05/23/02	Oates et al.			
	MP	2002/064659 0064653	05/30/02	Ladika et al.			
	MQ	2002/085192 0065193	05/30/02	Mackenzie et al.			
	MR	2002/0010077	01/24/02	Lue et al.			
	MS	2002/0013440	01/31/02	Agarwal et al.			
	MT	2002/0018264	02/07/02	Whiteker et al.			
	MU	2002/0040114	04/04/02	Loveday et al.			
	MV	2002/0086955	07/04/02	Kendrick			
	MW	2002/132823 0132923	09/19/02	Langohr et al.			
	MX	2003/0096896	05/22/03	Wang et al.			
KW	MY	2004/0034170	02/19/04	Brant			
EXAMINER /Katarzyna Wyrozebski Lee/				DATE CONSIDERED 10/25/2006			
*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPFP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next comment to applicant							

(\BPC\Law\Prosecutor\EMCC\Prosecutor\2003\B043\2003B043C-US-2001B043C-US-2004AUG09-SFCOND SUPPLEMENTAL IDS &amp; 1449.DOC


**SUPPLEMENTAL INFORMATION  
DISCLOSURE STATEMENT**
*(Use several sheets if necessary)*

ATTY. DOCKET NO.

2003B043C

SERIAL NO.

10/825,349

APPLICANT

Abhari, et al.

FILING DATE

April 15, 2004

GROUP

1713

**U.S. PATENT DOCUMENTS**

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
KW	AA	5,231,126	07-2-1993	Shi et al.	524	296	
	AB	6,747,114	06-08-2004	Karandinos, et al.	526	348.2	
	AC	6,774,069	08-10-2004	Zhou, et al.	442	328	
	AD	US 2002-0123538	09-05-2002	Zhou, et al.	523	176	
	AE	2003-078330 0078350	<del>11-14-2002</del>	Weng, et al.	526	160	04-23-2003
	AF	2004-048984 0048984	<del>08-13-2003</del>	Weng, et al.	525	245	03-11-2004
	AG	2004-0138392	<del>10/15/2003</del>	Jiang, et al.	526	114	07-15-2004
	AH	2004-127614 0127614	<del>10/15/2003</del>	Jiang, et al.	524	270	07-01-2004
	AI	2004-0220359	<del>4/15/2004</del>	Abhari, et al.	526	65	11-04-2004
	AJ	2004-0220336	<del>4/15/2004</del>	Abhari, et al.	525	70	11-04-2004
KW	AK	2004-0249046	<del>4/15/2004</del>	Abhari, et al.	524	474	12-09-2004

**FOREIGN PATENT DOCUMENTS**

		DOCUMENT NUMBER	PUBL DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
KW	AL	2316614	10-18-1973	DE				
	AM	1 295 926 A	03-26-2003	EP				
	AN	2407183	04-11-2003	CA				
	AO	02/36651 A	05-10-2002	WO				
	AP	2004/046214 A	06-03-2004	WO				
KW	AQ	2004/037872 A	05-06-2004	WO				

**OTHER DISCLOSURES (Including Author, Title, Date, Pertinent Pages of Publication, Etc.)**

KW	AR	Abstract of DE 2316614
KW	AS	Abstract of CA 2407183

EXAMINER

/Katarzyna Wyrozebski Lee/

DATE CONSIDERED

10/25/2006

\*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next comment to applicant